

**Search Notes**

Application/Control No.

10/665,053

Examiner

Shih-wen Hsieh

Applicant(s)/Patent under  
Reexamination

BYBEE ET AL.

Art Unit

2861

**SEARCHED**

Class	Subclass	Date	Examiner
347	85-87	12/6/2005	<i>SWH</i> SWH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
USPGPUB text search (see attached)12-06-05	12/6/2005	<i>SWH</i> SWH